Department of Physics

**Indian Institute of Technology Patna**

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**Requisition form for X-Ray Diffractometer**

1. USER and PAYMENT DETAILS

|  |  |  |  |
| --- | --- | --- | --- |
| Name, Affiliation | Department/Organization (In case of outside IIT P, give full postal address) | Contact details(phone number and e-mail id) | Payment confirmation(Please see the terms and conditions, to know about any additional charges for estimation) |
|  |  |  | Amount Paid:DD number/Transaction Reference:Date:Bank: |

1. SAMPLE DETAILS

|  |  |
| --- | --- |
| **No of Samples with sample ID (s):** |  |
| Nature of sample | Type of sample: Thin film/Pellet/PowderSample is non-hygroscopic/hygroscopic. If hygroscopic, high/lowWhether the sample is fluorescent for X-ray? (Yes/No): Whether the sample is volatile w. r. t X-ray? (Yes/No):Any other sample info relevant to XRD… |

1. EXPERIMENTAL DETAILS REQUIRED

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| --- |
| 1. Type of the measurement: XRR/XRD/SAXS/Texture/Pole figure
2. Mode of operation: Focused beam/Parallel beam/Scattering
3. 2θ range: \_\_\_\_\_\_\_ to \_\_\_\_\_\_\_, Scan rate: \_\_\_\_\_ degree/minute, Scan step \_\_\_\_\_\_\_ degree
4. Glancing angle required (Only for parallel beam): \_\_\_\_\_\_\_\_\_ degree
5. If specific target power is required, mention with justification.

Any requirement specific to XRD |

Signature of the user

Name & Signature of the Supervisor

Signature of HoD, user department

(With date and official seal)

FOR OFFICE USE ONLY

1. SLOT ALLOTMENT DETAILS

Job Order Number:

Assigned date and time of execution: No. of slots allotted:

Signature of staff operator/in-charge Signature of Faculty in-charge

**Terms and Conditions for using the Facilities**

1. The mentioned charges are **excluding any applicable GST.**
2. The charges mentioned are **per slot of one hour** unless otherwise mentioned in specific tables mentioning analytical charges. The slot time includes the sample loading time. The actual **number of samples** to be done in a slot **depends upon the specific requirement** of the user or the instrument feasibility. In case a single sample takes more than one 1 hr (may be due to nature of measurement or due to the specific requirement from user), the **total charges will be suitable integer multiplication of the charges for one slot**.
3. Samples should be ready to use for/in/with XRD.
4. Users may contact the concerned operator for the experiment-specific preparation/treatment of sample.
5. The charges mentioned are only for measurement and providing the raw data (in the format possible with the instrument) thereafter. No analysis/software compatibility of data can be claimed later. For consultancy on data analysis, the user may contact the experts separately through head of the department.
6. Measurements are subject to the corresponding instrument being in working condition. The status of each instrumental facility will be updated regularly.
7. In case of the measurement remains incomplete due to malfunctioning or any unforeseen situation, the user will be notified. Depending upon user’s discretion, either the payment received will be returned or the measurement will be carried out after the instrument becomes functional (maximum waiting period also may be informed by user).

**Analytical charges related to experiments performed with X-Ray Diffractometer**

|  |  |
| --- | --- |
| Name of the facility | Analytical charges (in INR, per hour)  |
| Users from external academic institutes | Users from Industries /R & D laboratories |
| X-Ray Diffractometer (XRD) | 1500 | 3000 |

\*For any specific customized measurement/testing, the analytical charges can be estimated in consultation with Physics department.